

<b>Notice of References Cited</b>	Application/Control No. 10/626,344	Applicant(s)/Patent Under Reexamination CHO ET AL.	
	Examiner John J. Zimmerman	Art Unit 1775	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,938,923	07-1990	Kujiraoka et al.	420/509
	B	US-5,658,664	08-1997	Uno et al.	428/364
	C	US-5,945,065 A	08-1999	Kikuchi et al.	420/507
	D	US-6,063,213 A	05-2000	Ogasa, Kazuo	148/430
	E	US-6,123,786 A	09-2000	Uchiyama et al.	148/430
	F	US-6,492,593 B2	12-2002	Murai et al.	174/94R
	G	US-6,700,199 B2	03-2004	Moon et al.	257/741
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	56-088328	07-1981	Japan	Hayashi et al.	---
	O	56-088329	07-1981	Japan	Hayashi et al.	---
	P	03-257129	11-1991	Japan	Hosoda et al.	---
	Q	06-145842	05-1994	Japan	Kitamura	---
	R	2000-040710	02-2000	Japan	Naito	---
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.